

FORM HDP-1449 (Based on Form PTO-1449)

**PATENT AND TRADEMARK OFFICE  
INFORMATION DISCLOSURE CITATION**  
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Sheet 1 of 2

ATTORNEY DOCKET NO.

1740-000036/US

SERIAL NO.

10/753,401

APPLICANT

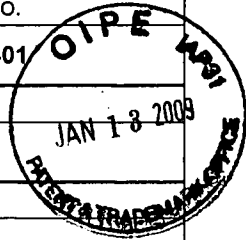
Jin Yong KIM et al.

FILING DATE

January 9, 2004

GROUP

2627

**U.S. PATENT DOCUMENTS**

Ref. Desig.	Examiner's Initials	Document Number	Date	Name	Class/ Subclass	(If appropriate) Filing Date
1		2005/0213483 A1	09-29-2005	Tomita et al.		
2		2003/0012099 A1	01-16-2003	Sako et al.		
3		2002/0097648 A1	07-25-2002	Iida		
4		2002/0064277 A1	05-30-2002	Kuribayashi et al.		
5		2002/0027990 A1	03-07-2002	Sako et al.		
6		6,157,606	12-05-2000	Inazawa et al.		
7		5,656,348	08-12-1997	Kudo et al.		
8		5,570,339	10-29-1996	Nagano		
9		4,419,750	12-06-1983	Howe		

**FOREIGN PATENT DOCUMENTS**

Ref. Desig.	Examiner's Initials	Document Number	Date	Country	Class/ Subclass	Translation Yes No	
10		CN 1135632 A	11-13-1996	China		Abstract	
11		EP 1 033 703 A2	09-06-2000	EPO			
12		EP 0 715 301 A2	06-05-1996	EPO			
13		JP 2001-052338	02-23-2001	Japan		Abstract	
14		JP 11-045508	02-16-1999	Japan		Abstract	
15		JP 09-055731	02-25-1997	Japan		Abstract	
16		JP 05-314731	11-26-1993	Japan		Abstract	
17		WO 01/93262 A2	12-06-2001	WIPO			
18		WO 01/29832 A1	04-26-2001	WIPO			

Examiner: /Parul Gupta/

Date Considered: 03/14/2009

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	FILING DATE	GROUP
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OTHER DOCUMENTS (including Author, Title, Date, Pertinent Pages, etc.)		
Ref. Desig.	Examiner's Initials	
19		Office Action issued February 10, 2006 by the Chinese Patent Office in counterpart Chinese Patent Application No. 03800943.9 (with English language translation)
20		Supplemental Search Report issued September 23, 2005 by the European Patent Office in counterpart European Patent Application No. 03757210.4-2210
21		Office Action issued June 12, 2007 by the Japanese Patent Office in counterpart Japanese Patent Application No. 2004-512129
22		Office Action issued November 14, 2006 by the Japanese Patent Office in counterpart Japanese Patent Application No. 2004-512129
23		Office Action issued July 31, 2008 by the Korean Patent Office in counterpart Korean Patent Application No. 10-2002-0031744
24		Office Action issued April 30, 2008 by the U.S. Patent and Trademark Office in counterpart U.S. Patent Application No. 10/485,912
25		Office Action issued October 12, 2007 by the U.S. Patent and Trademark Office in counterpart U.S. Patent Application No. 10/485,912
26		Office Action issued September 22, 2006 by the U.S. Patent and Trademark Office in counterpart U.S. Patent Application No. 10/485,912
27		International Search Report issued September 24, 2003 in counterpart International Patent Application No. PCT/KR03/01109

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